MSKSEMI















ESD

TVS

TSS

MOV

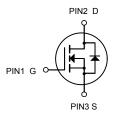
GDT

PLED

Broduct data sheet







N-Channel MOSFET

TO-252

Description

The AOD442G-MS uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 60V I_D = 50 A$

 $R_{DS(ON)}$ < 13m Ω @ V_{GS} =10V

Application

Battery protection

Load switch

Uninterruptible power supply

Absolute Maximum Ratings (T_C=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units	
VDS	Drain-Source Voltage	60		
Vgs	Gate-Source Voltage ±20		V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹ 50		Α	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹ 25		А	
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹ 7.4		А	
ID@T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹ 6		А	
Ідм	Pulsed Drain Current ² 90		А	
EAS	Single Pulse Avalanche Energy ³ 39.2		mJ	
las	Avalanche Current 28		А	
P _D @T _C =25°C	Total Power Dissipation ⁴ 45		W	
P _D @T _A =25°C	Total Power Dissipation ⁴ 2		W	
Тѕтс	Storage Temperature Range -55 to 150		°C	
TJ	Operating Junction Temperature Range -55 to 150		°C	
R ₀ JA	Thermal Resistance Junction-Ambient ¹	unction-Ambient ¹ 62 °C/M		



Thermal Neoletanes varieties Galleties 2.0	ReJc	Thermal Resistance Junction-Case ¹	2.8	°C/W
--	------	---	-----	------

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60			V
△BVpss/△TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA		0.057		V/°C
		V _{GS} =10V , I _D =20A		11	15	
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =10A		15	20	mΩ
V _G S(th)	Gate Threshold Voltage		1.2		2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =250uA		-5.68		mV/°C
		V_{DS} =48V , V_{GS} =0V , T_{J} =25 $^{\circ}$ C			1	
Ipss	Drain-Source Leakage Current	V_{DS} =48V , V_{GS} =0V , T_{J} =55 $^{\circ}$ C			5	uA
Igss	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =15A		45		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7		Ω
Q_g	Total Gate Charge (4.5V)			19.3		
Qgs	Gate-Source Charge	V _{DS} =48V , V _{GS} =4.5V , I _D =15A		7.1		nC
Q _{gd}	Gate-Drain Charge			7.6		
T _{d(on)}	Turn-On Delay Time			7.2		
Tr	Rise Time	V _{DD} =30V , V _{GS} =10V , —R _G =3.3 ,		50		
T _{d(off)}	Turn-Off Delay Time	RG-3.3 , ID=15A		36.4		ns
T _f	Fall Time	_ID-13A		7.6		
C _{iss}	Input Capacitance			2423		
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		145		pF
Crss	Reverse Transfer Capacitance			97		
Is	Continuous Source Current ^{1,5}				35	Α
Іѕм	Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			80	Α
Vsp	Diode Forward Voltage ²	V _{GS} =0V , I _S =A , T _J =25°C			1	V
t _{rr}	Reverse Recovery Time	I=-45A - 41/4±-400 A /···-		16.3		nS
Q _{rr}	Reverse Recovery Charge	IF=15A , dI/dt=100A/μs , T _J =25°C		11		nC

Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- $3. The \ EAS \ data \ shows \ Max. \ rating \ . \ The \ test \ condition \ is \ VDD=25V,VGS=10V,L=0.1mH,IAS=28A$
- 4. The power dissipation is limited by 150° C junction temperature 5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation



Typical Characteristics

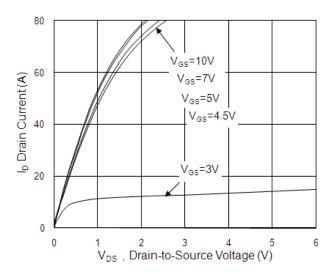


Fig.1 Typical Output Characteristics

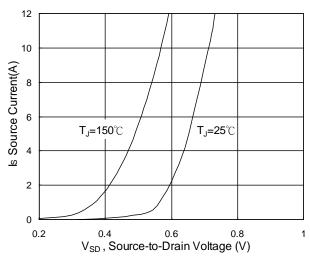


Fig.3 Forward Characteristics of Reverse

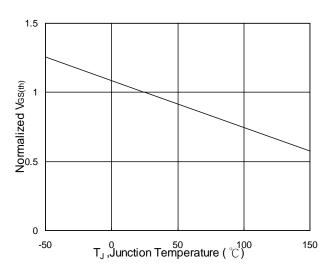


Fig.5 Normalized V_{GS(th)} v.s T_J

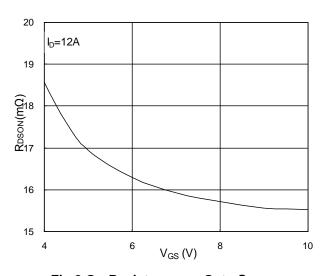


Fig.2 On-Resistance v.s Gate-Source

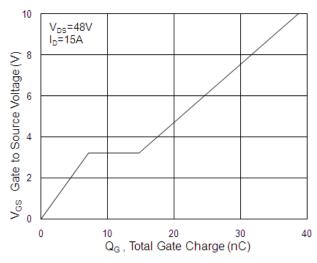


Fig.4 Gate-Charge Characteristics

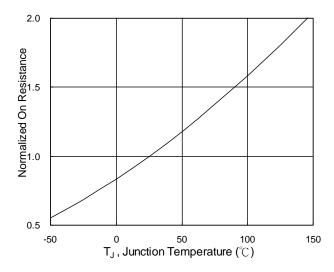
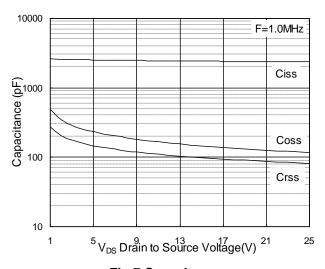


Fig.6 Normalized R_{DSON} v.s T_J







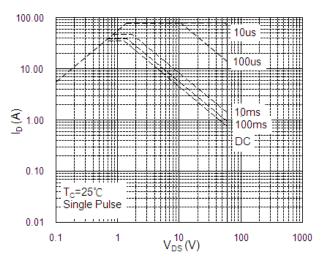


Fig.7 Capacitance

Fig.8 Safe Operating Area

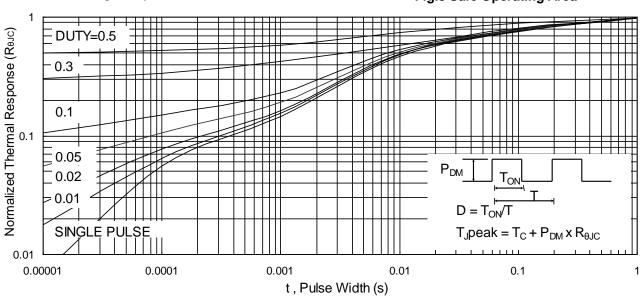


Fig.9 Normalized Maximum Transient Thermal Impedance

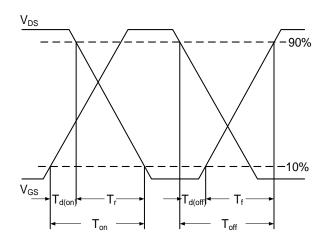


Fig.10 Switching Time Waveform

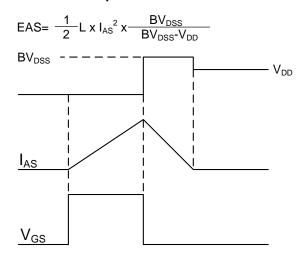
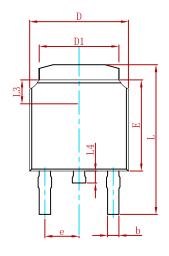


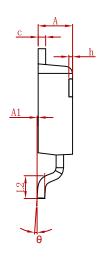
Fig.11 Unclamped Inductive Switching Waveform

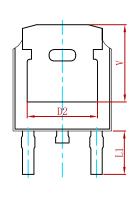




PACKAGE MECHANICAL DATA

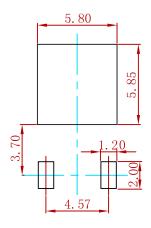






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900	REF.	0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600	REF.	0.063	REF.
L4	0.600	1.000	0.024	0.039
•				·
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AOD442G-MS	TO-252	2500



Attention

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specificationsof any andall MSKSEMI Semiconductor products described orcontained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possiblethat these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuitsfor safedesign, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringementsof intellectual property rights or other rightsof third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.